

SN54LV125A, SN74LV125A QUADRUPLE BUS BUFFER GATES WITH 3-STATE OUTPUTS

SCES124D – DECEMBER 1997 – REVISED JULY 1998

- **EPIC™** (Enhanced-Performance Implanted CMOS) Process
- Typical V_{OLP} (Output Ground Bounce) < 0.8 V at V_{CC} , $T_A = 25^\circ\text{C}$
- Typical V_{OHV} (Output V_{OH} Undershoot) > 2 V at V_{CC} , $T_A = 25^\circ\text{C}$
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model ($C = 200$ pF, $R = 0$)
- Package Options Include Plastic Small-Outline (D, NS), Shrink Small-Outline (DB), Thin Very Small-Outline (DGV), and Thin Shrink Small-Outline (PW) Packages, Ceramic Flat (W) Packages, Chip Carriers (FK), and DIPs (J)

description

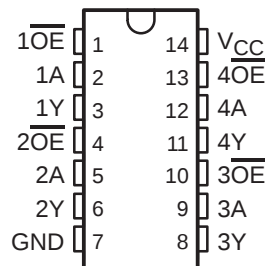
The 'LV125A quadruple bus buffer gates are designed for 2-V to 5.5-V V_{CC} operation.

These devices feature independent line drivers with 3-state outputs. Each output is disabled when the associated output-enable ($\overline{OE}$) input is high.

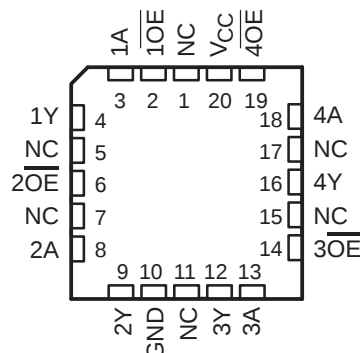
To ensure the high-impedance state during power up or power down, $\overline{OE}$ should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN54LV125A is characterized for operation over the full military temperature range of -55°C to 125°C . The SN74LV125A is characterized for operation from -40°C to 85°C .

SN54LV125A . . . J OR W PACKAGE
SN74LV125A . . . D, DB, DGV, NS, OR PW PACKAGE
(TOP VIEW)



SN54LV125A . . . FK PACKAGE
(TOP VIEW)



NC – No internal connection

FUNCTION TABLE
(each buffer)

INPUTS		OUTPUT Y
$\overline{OE}$	A	
L	H	H
L	L	L
H	X	Z



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**TEXAS
INSTRUMENTS**

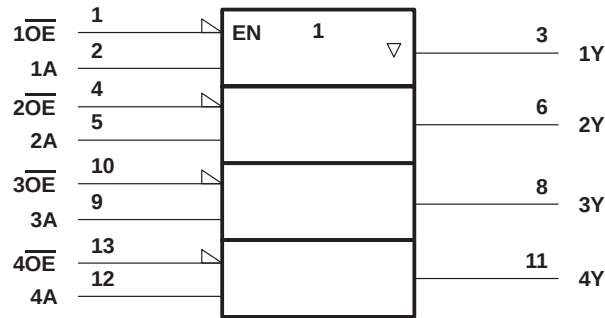
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WITH 3-STATE OUTPUTS

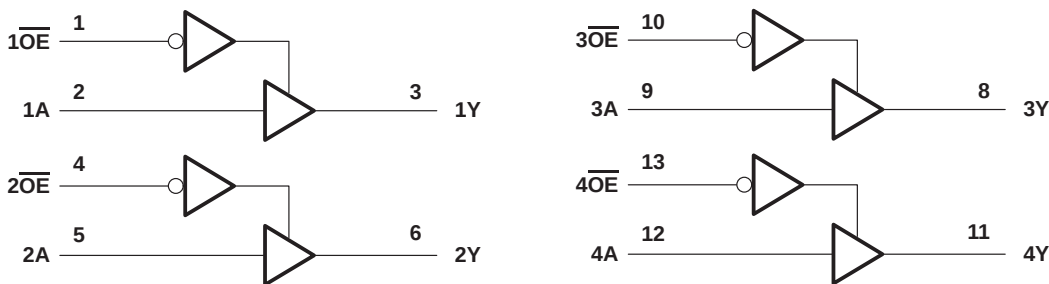
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logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.
Pin numbers shown are for the D, DB, DGV, J, NS, PW, and W packages.

logic diagram (positive logic)



Pin numbers shown are for the D, DB, DGV, J, NS, PW, and W packages.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V_{CC}	–0.5 V to 7 V
Input voltage range, V_I (see Note 1)	–0.5 V to 7 V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–20 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$)	±50 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	±35 mA
Continuous current through V_{CC} or GND	±70 mA
Package thermal impedance, θ_{JA} (see Note 3):	
D package	127°C/W
DB package	158°C/W
DGV package	182°C/W
NS package	127°C/W
PW package	170°C/W
Operating free-air temperature range, T_A	–40°C to 85°C
Storage temperature range, T_{stg}	–65°C to 150°C

‡ Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES:
1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
 2. This value is limited to 7 V maximum.
 3. The package thermal impedance is calculated in accordance with JESD 51.

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recommended operating conditions (see Note 4)

			SN54LV125A		SN74LV125A		UNIT
			MIN	MAX	MIN	MAX	
V _{CC}	Supply voltage		2	5.5	2	5.5	V
V _{IH}	High-level input voltage	V _{CC} = 2 V	1.5		1.5		V
		V _{CC} = 2.3 V to 2.7 V	V _{CC} × 0.7		V _{CC} × 0.7		
		V _{CC} = 3 V to 3.6 V	V _{CC} × 0.7		V _{CC} × 0.7		
		V _{CC} = 4.5 V to 5.5 V	V _{CC} × 0.7		V _{CC} × 0.7		
V _{IL}	Low-level input voltage	V _{CC} = 2 V		0.5		0.5	V
		V _{CC} = 2.3 V to 2.7 V		V _{CC} × 0.3		V _{CC} × 0.3	
		V _{CC} = 3 V to 3.6 V		V _{CC} × 0.3		V _{CC} × 0.3	
		V _{CC} = 4.5 V to 5.5 V		V _{CC} × 0.3		V _{CC} × 0.3	
V _I	Input voltage		0	5.5	0	5.5	V
V _O	Output voltage	High or low state	0	V _{CC}	0	V _{CC}	V
		3-state	0	5.5	0	5.5	
I _{OH}	High-level output current	V _{CC} = 2 V		–50		–50	μA
		V _{CC} = 2.3 V to 2.7 V		–2		–2	
		V _{CC} = 3 V to 3.6 V		–8		–8	mA
		V _{CC} = 4.5 V to 5.5 V		–16		–16	
I _{OL}	Low-level output current	V _{CC} = 2 V		50		50	μA
		V _{CC} = 2.3 V to 2.7 V		2		2	
		V _{CC} = 3 V to 3.6 V		8		8	mA
		V _{CC} = 4.5 V to 5.5 V		16		16	
Δt/Δv	Input transition rise or fall rate	V _{CC} = 2.3 V to 2.7 V	0	200	0	200	ns/V
		V _{CC} = 3 V to 3.6 V	0	100	0	100	
		V _{CC} = 4.5 V to 5.5 V	0	20	0	20	
T _A	Operating free-air temperature		–55	125	–40	85	°C

NOTE 4: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	SN54LV125A			SN74LV125A			UNIT
			MIN	TYP	MAX	MIN	TYP	MAX	
V _{OH}	I _{OH} = –50 μA	2 V to 5.5 V	V _{CC} –0.1			V _{CC} –0.1			V
	I _{OH} = –2 mA	2.3 V	2			2			
	I _{OH} = –8 mA	3 V	2.48			2.48			
	I _{OH} = –16 mA	4.5 V	3.8			3.8			
V _{OL}	I _{OL} = 50 μA	2 V to 5.5 V	0.1			0.1			V
	I _{OL} = 2 mA	2.3 V	0.4			0.4			
	I _{OL} = 8 mA	3 V	0.44			0.44			
	I _{OL} = 16 mA	4.5 V	0.55			0.55			
I _I	V _I = V _{CC} or GND	5.5 V	±1			±1			μA
I _{OZ}	V _O = V _{CC} or GND	5.5 V	±5			±5			μA
I _{CC}	V _I = V _{CC} or GND, I _O = 0	5.5 V	20			20			μA
I _{off}	V _I or V _O = 0 to 5.5 V	0 V	5			5			μA
C _i	V _I = V _{CC} or GND	3.3 V	2			2			pF

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switching characteristics over recommended operating free-air temperature range,
 $V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$ (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	LOAD CAPACITANCE	$T_A = 25^\circ\text{C}$			SN54LV125A		SN74LV125A		UNIT
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
t_{pd}^*	A	Y	$C_L = 15\text{ pF}$	6.8	13		1	15.5	1	15.5	ns
t_{en}^*	$\overline{\text{OE}}$	Y		7	13		1	15.5	1	15.5	
t_{dis}^*	$\overline{\text{OE}}$	Y		5.1	14.7		1	17	1	17	
t_{pd}	A	Y	$C_L = 50\text{ pF}$	8.7	16.5		1	18.5	1	18.5	ns
t_{en}	$\overline{\text{OE}}$	Y		8.8	16.5		1	18.5	1	18.5	
t_{dis}	$\overline{\text{OE}}$	Y		7.3	18.2		1	20.5	1	20.5	
$t_{sk(o)}^\dagger$					2					2	

* On products compliant to MIL-PRF-38535, this parameter is not production tested.

† Skew between any two outputs of the same package switching in the same direction

switching characteristics over recommended operating free-air temperature range,
 $V_{CC} = 3.3\text{ V} \pm 0.3\text{ V}$ (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	LOAD CAPACITANCE	$T_A = 25^\circ\text{C}$			SN54LV125A		SN74LV125A		UNIT
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
t_{pd}^*	A	Y	$C_L = 15\text{ pF}$	4.8	8		1	9.5	1	9.5	ns
t_{en}^*	$\overline{\text{OE}}$	Y		4.8	8		1	9.5	1	9.5	
t_{dis}^*	$\overline{\text{OE}}$	Y		4.1	9.7		1	11.5	1	11.5	
t_{pd}	A	Y	$C_L = 50\text{ pF}$	6.1	11.5		1	13	1	13	ns
t_{en}	$\overline{\text{OE}}$	Y		6.2	11.5		1	13	1	13	
t_{dis}	$\overline{\text{OE}}$	Y		5.5	13.2		1	15	1	15	
$t_{sk(o)}^\dagger$					1.5					1.5	

* On products compliant to MIL-PRF-38535, this parameter is not production tested.

† Skew between any two outputs of the same package switching in the same direction

switching characteristics over recommended operating free-air temperature range,
 $V_{CC} = 5\text{ V} \pm 0.5\text{ V}$ (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	LOAD CAPACITANCE	$T_A = 25^\circ\text{C}$			SN54LV125A		SN74LV125A		UNIT
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
t_{pd}^*	A	Y	$C_L = 15\text{ pF}$	3.4	5.5		1	6.5	1	6.5	ns
t_{en}^*	$\overline{\text{OE}}$	Y		3.4	5.1		1	6	1	6	
t_{dis}^*	$\overline{\text{OE}}$	Y		3.2	6.8		1	8	1	8	
t_{pd}	A	Y	$C_L = 50\text{ pF}$	4.3	7.5		1	8.5	1	8.5	ns
t_{en}	$\overline{\text{OE}}$	Y		4.4	7.1		1	8	1	8	
t_{dis}	$\overline{\text{OE}}$	Y		4	8.8		1	10	1	10	
$t_{sk(o)}^\dagger$					1					1	

* On products compliant to MIL-PRF-38535, this parameter is not production tested.

† Skew between any two outputs of the same package switching in the same direction

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noise characteristics, $V_{CC} = 3.3\text{ V}$, $C_L = 50\text{ pF}$, $T_A = 25^\circ\text{C}$ (see Note 5)

PARAMETER		SN74LV125A			UNIT
		MIN	TYP	MAX	
$V_{OL(P)}$	Quiet output, maximum dynamic V_{OL}		0.36	0.8	V
$V_{OL(V)}$	Quiet output, minimum dynamic V_{OL}		-0.27	-0.8	V
$V_{OH(V)}$	Quiet output, minimum dynamic V_{OH}		3.04		V
$V_{IH(D)}$	High-level dynamic input voltage	2.31			V
$V_{IL(D)}$	Low-level dynamic input voltage			0.99	V

NOTE 5: Characteristics are for surface-mount packages only.

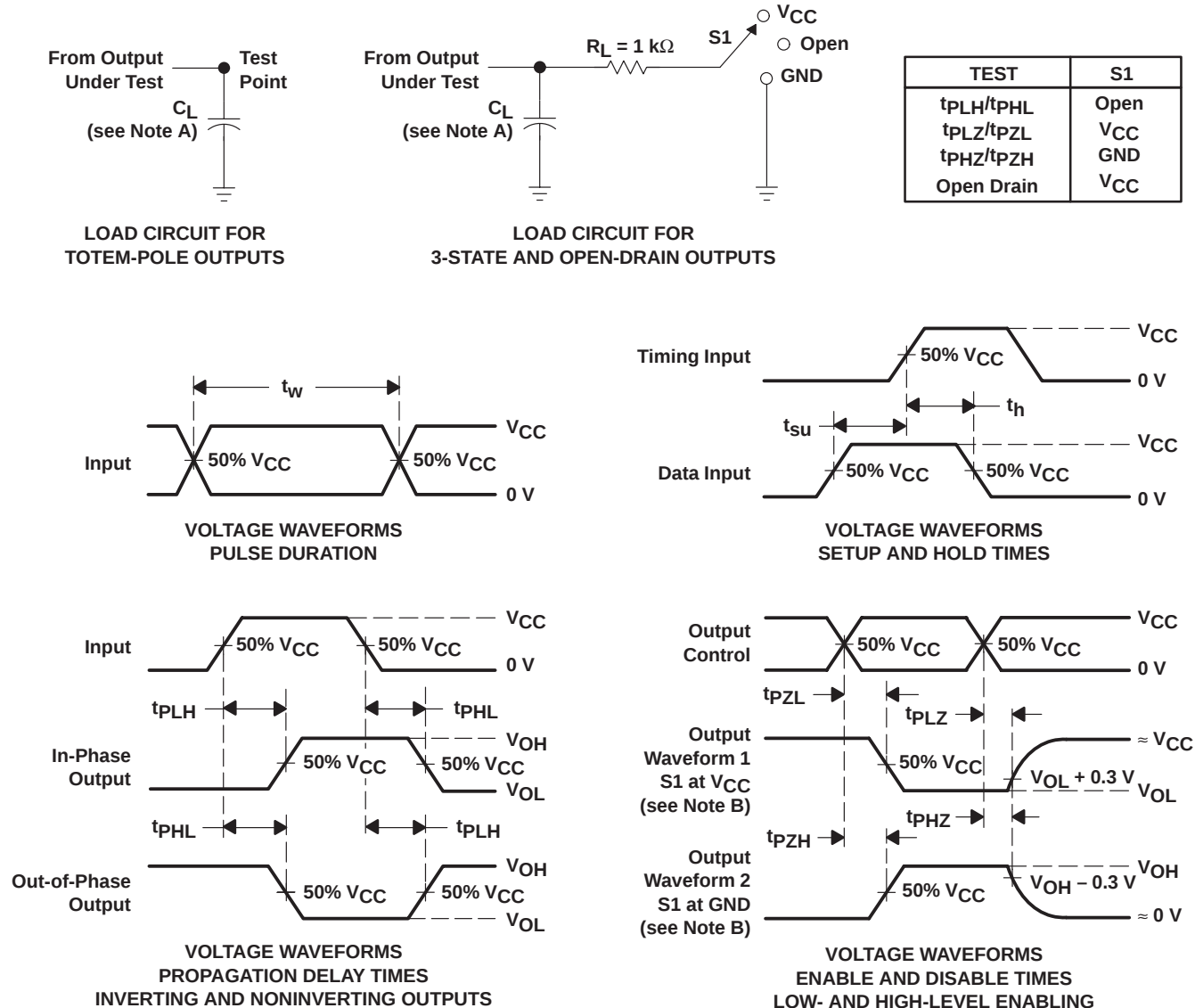
operating characteristics, $T_A = 25^\circ\text{C}$

PARAMETER		TEST CONDITIONS	V_{CC}	TYP	UNIT
C_{pd}	Power dissipation capacitance		3.3 V	15.5	pF
	Outputs enabled	$C_L = 50\text{ pF}$, $f = 10\text{ MHz}$	5 V	17.6	

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PARAMETER MEASUREMENT INFORMATION



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 1\text{ MHz}$, $Z_O = 50\ \Omega$, $t_r \leq 3\text{ ns}$, $t_f \leq 3\text{ ns}$.
 - D. The outputs are measured one at a time with one input transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PHL} and t_{PLH} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

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